

**Search Notes**

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10/567,780

Examiner

Nguyen N. Hanh

Applicant(s)/Patent under  
Reexamination

AKITA ET AL.

Art Unit

2834

**SEARCHED**

Class	Subclass	Date	Examiner
310	52	11/24/2006	HN
310	54	11/24/2006	HN
310	58	11/24/2006	HN
310	64	11/24/2006	HN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR